

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1672SERIAL NO.
09/943.199LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Kristy A. Campbell, et al.FILING DATE
August 29, 2001GROUP
2818

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
DV	AA	09/797,635		Moore			03/01/2001
	AB	09/732,968		Gilton			12/08/2000
	AC	09/943,190		Campbell, et al.			08/29/2001
	AD	09/943,187		Campbell, et al.			08/29/2001
	AE	09/779,983		Moore			02/08/2001
	AF	5,238,862	08/24/93	Blalock et al.			
	AG	5,360,981	11/01/94	Owen et al.			
	AH	5,761,115	06/02/98	Kozicki et al.			
	AI	5,896,312	04/20/99	Kozicki et al.			
	AJ	5,914,893	06/22/99	Kozicki et al.			
DV	AK	6,084,796	07/04/00	Kozicki et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DV	AR		Hirose, et al., "High Speed Memory Behavior and Reliability of an Amorphous As ₂ S ₃ Film Doped with Ag", July 17, 1980, pps. K187-K190.
DV	AS		Hirose, et al., "Polarity-dependent memory switching and behavior of Ag dendrite in Ag-photodoped amorphous As ₂ S ₃ films", Journal of Applied Physics, Vol. 47, No. 6, June, 1976, pps. 2767-2772.
DV	AT		Kawaguchi, et al., "Optical, electrical, and structural properties of amorphous Ag-Ge-S and Ag-Ge-Se films and comparison of photoinduced and thermally induced phenomena of both systems", Journal of Applied Physics, 79, June 1996, pps. 9096-9104.

EXAMINER

shuland

DATE CONSIDERED

01/08/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1672SERIAL NO.
09/943,199LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Kristy A. Campbell, et alFILING DATE
August 29, 2001GROUP
2818

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DV	AR		Kluge, et al. "Silver photodiffusion in amorphous Ge ₂ Se ₁₀ ", Journal of Non-Crystalline Solids 124 (1990) pps. 186-193
DV	AS		Kolobov, A.V., "Photodoping of amorphous chalcogenides by metals", Advances in Physics, 1991, Vol. 40, No. 5, pps. 625-684.
DV	AT		Mitkova, et al. "Dual Chemical Role of Ag as an Additive in Chalcogenide Glasses", Physical Review Letters, Vol. 83, No. 19, pps. 3848-3851

EXAMINER

Shidant

DATE CONSIDERED

01/08/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1672SERIAL NO.
09/943,199LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Kristy A. Campbell, et alFILING DATE
August 29, 2001GROUP
2818

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DV	AR		Mitkova, "Insulating and Semiconducting Glasses", Editor: P. Boolchand, World Scientific, New Jersey, 2000, pps 813-843.
DV	AS		Axon Technologies Corporation, TECHNOLOGY DESCRIPTION: Programmable Metallization Cell (PMC).
			(pre-July 7, 2000) pp 1-6
DV	AT		Shimakawa et al., Photoinduced effects and metastability in amorphous semiconductors and insulators.
			44 ADVANCES IN PHYSICS No. 6, 475-588 (Taylor & Francis Ltd 1995)

EXAMINER

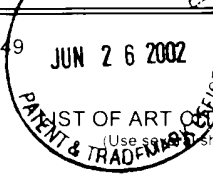
Strulant

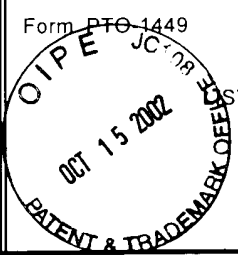
DATE CONSIDERED

01/08/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1672		SERIAL NO. 09/943.199	
<div style="display: flex; align-items: center; justify-content: center;"> <div style="border: 1px solid black; border-radius: 50%; padding: 10px; text-align: center; margin-right: 10px;"> 1 P A R T I C I P A N T S O F F I C E J U N 262002 </div> <div> LIST OF ARTS CITED BY APPLICANT (Use several sheets if necessary) </div> </div>				APPLICANT: Kristy A. Campbell et al.			
				FILING DATE 08/29/01		GROUP 2818	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
DV	AA	09/921,518	Moore (As filed and amended)			08/01/2001	
	AB	09/999,883	Moore et al. (as filed)			03/01/2001	
	AC	10/061,825	Gilton et al. (as filed)			01/31/2002	
	AD	4,405,710	09/20/83	Balasubramanyam et al.	430	311	
	AE	4,419,421	12/06/83	Wilchelhaus et al.	429	191	
	AF	4,499,557	02/12/85	Holmberg et al.	365	163	
	AG	5,315,131	05/24/94	Kishimoto et al.	257	57	
	AH	5,350,484	09/27/94	Gardner et al.	156	628	
	AI	5,512,328	04/30/96	Yoshimura et al.	427	498	
DV	AJ	5,512,773	04/30/96	Wolf et al.	257	471	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
DV	AK	56126916 A	05.10.81	Abstract: Japan (Akira et al.)			X
	AL	00/48196 A1	17.08.00	WIPO (Kozicki et al.)			
	AM	09/21542 A1	14.03.02	WIPO (Kozicki et al.)			
	AN						
DV	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AP		<div style="display: flex; align-items: center; justify-content: center;"> <div style="writing-mode: vertical-rl; transform: rotate(180deg);"> RECEIVED JUN-2 2003 TECHNICAL CENTER 2800 </div> </div>				
	AQ						
	AR						
EXAMINER <i>Shulard</i>				DATE CONSIDERED 01/08/03			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1672		SERIAL NO. 09/943,199		
LIST OF ART CITED BY APPLICANT <small>(Use separate sheets if necessary)</small>						APPLICANT: Kristy A. Campbell et al.				
						FILING DATE 08/29/01		GROUP 2818		
U.S. PATENT DOCUMENTS										
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate				
DV	AA	5,846,889	12/08/98	Harbison et al.	501	40				
	AB	6,117,720	09/12/00	Harshfield	438	238				
	AC	6,143,604	11/07/00	Chiang et al.	438	253				
	AD	6,177,338 B1	01/23/01	Liaw et al.	438	629				
DV	AE	6,350,679 B1	02/26/02	McDaniel et al.	438	634				
	AF									
	AG									
	AH									
	AI									
	AJ									
FOREIGN PATENT DOCUMENTS										
	Document Number	Date	Country	Class	Subclass	Translation				
						Yes	No			
	AK									
	AL									
	AM									
	AN									
	AO									
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)										
	AP									
	AQ									
	AR									
EXAMINER <i>ghidani</i>				DATE CONSIDERED <i>01/08/03</i>						
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>										

Form PTO-1449 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1672		SERIAL NO. 09/943,199	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Kristy A. Campbell et al.			
FILING DATE August 29, 2001				GROUP 2818			

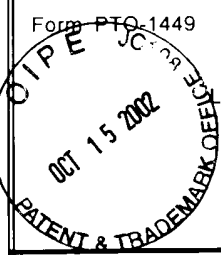
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DV	AA	3,622,319	11/23/71	Sharp	96	27	
	AB	3,743,847	07/03/73	Boland	250	510	
	AC	4,269,935	05/26/81	Masters et al.	430	323	
	AD	4,312,938	01/26/82	Drexler et al.	430	496	
	AE	4,320,191	03/16/82	Yoshikawa et al.	430	296	
	AF	4,795,657	01/03/89	Formigoni et al.	427	96	
	AG	4,847,674	07/11/89	Silwa et al.	357	67	
	AH	5,177,567	01/05/93	Klersy et al.	257	4	
	AI	5,219,788	06/15/93	Abernathey et al.	437	187	
	AJ	5,726,083	03/10/98	Takaishi	438	210	
DV	AK	5,751,012	05/12/98	Wolstenholme et al.	257	5	

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL						
	AM						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
DV	AN		Das et al., <i>Theory of the characteristic curves of the silver chalcogenide glass inorganic photoresists</i> , 54 APPL. PHYS. LETT., No. 18, pp. 1745-1747 (May 1989).
	AO		Helbert et al., <i>Intralevel hybrid resist process with submicron capability</i> , SPIE Vol. 333
			SUBMICRON LITHOGRAPHY pp. 24-29 (1982)
DV	AP		Hilt, DISSERTATION: <i>Materials Characterization of Silver Chalcogenide Programmable Metallization</i>
			Cells, Arizona State University, pp. title page-114 (UMI Company, May 1999).

EXAMINER <i>gudaul</i>	DATE CONSIDERED <i>01/08/03</i>
------------------------	---------------------------------

*EXAMINER. Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1672		SERIAL NO. 09/943,199	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)						APPLICANT: Kristy A. Campbell et al.	
FILING DATE August 29, 2001						GROUP 2818	

U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DV	AA	5,789,277	08/04/98	Zahorik et al.	438	95	
	AB	5,841,150	11/24/98	Gonzalez et al.	257	3	
	AC	5,920,788	07/06/99	Reinberg	438	466	
	AD	5,998,066	12/07/99	Block et al.	430	5	
	AE	6,077,729	06/20/00	Harshfield	438	128	
	AF	6,236,059 B1	05/22/01	Wolstenholme et al.	257	3	
	AG	6,297,170 B1	10/02/01	Gabriel et al.	438	738	
	AH	6,300,684 B1	10/09/01	Gonzalez et al.	257	774	
	AI	6,316,784 B1	11/13/01	Zahorik et al.	257	3	
	AJ	6,329,606 B1	12/11/01	Freyman et al.	174	260	
DV	AK	6,348,365	02/19/02	Moore et al.	438	130	

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL						
	AM						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
DV	AN		Holmquist et al., <i>Reaction and Diffusion in Silver-Arsenic Chalcogenide Glass Systems</i> ,
			62 J. AMER. CERAMIC SOC., Nos. 3-4, pp. 183-188 (Mar.-Apr. 1979).
	AO		Huggett et al., <i>Development of silver sensitized germanium selenide photoresist by reactive</i>
			<i>sputter etching in SF₆</i> , 42 APPL. PHYS. LETT., No. 7, pp. 592-594 (April 1983).
DV	AP		Kawaguchi et al., <i>Mechanism of photosurface deposition</i> , 164-166 J. NON-CRYST. SOLIDS,
			pp. 1231-1234 (1993).

EXAMINER <i>Struland</i>	DATE CONSIDERED <i>01/08/03</i>
--------------------------	---------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1672SERIAL NO.
09/943,199LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT: Kristy A. Campbell et al.

FILING DATE
August 29, 2001GROUP
2818

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DV	AA	6,376,284 B1	04/23/02	Gonzalez et al.	438	129	
	AB	6,391,688 B1	05/21/02	Gonzalez et al.	438	128	
	AC	6,414,376 B1	07/02/02	Thakur et al.	257	640	
	AD	6,418,049 B1	07/09/02	Kozicki et al.	365	174	
DV	AE	6,423,628 B1	07/23/02	Li et al.	438	622	
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DV	AN	McHardy et al., <i>The dissolution of metals in amorphous chalcogenides and the effects of electron and ultraviolet radiation</i> , 20 J. PHYS. C: SOLID STATE PHYS., pp. 4055-4075 (1987).
	AO	Miyatani, <i>Electrical Properties of Ag₂Se</i> , 13 J. Phys. Soc. Japan, p. 317 (1958).
DV	AP	Mizusaki et al. <i>Kinetic Studies on the Selenization of Silver</i> , 47 BUL. CHEM. SOC. JAPAN., No. 11
		pp. 2851-2855 (November 1974).

EXAMINER

f. Ireland

DATE CONSIDERED

01/08/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1672		SERIAL NO. 09/943,199	
		APPLICANT: Kristy A. Campbell et al.			
		FILING DATE August 29, 2001		GROUP 2818	

Form 1
 OCT 15 2002
 PATENT & TRADEMARK OFFICE

U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DV	AA	10/077,867		Campbell et al. (as filed)			02/20/2002
DV	AB	10/232,757		Li, et al. (as filed)			08/29/2002
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL						
	AM						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
DV	AN	Owen et al., <i>Metal-Chalcogenide Photoresists for High Resolution Lithography and Sub-Micron Structures</i> , NANOSTRUCTURE PHYSICS AND FABRICATION, pp. 447-451 (Academic Press, 1989).	
	AO	Safran et al., <i>TEM study of Ag₂Se developed by the reaction of polycrystalline silver films and selenium</i> , 317 THIN SOLID FILMS, pp. 72-76 (1998).	
DV	AP	Shimizu et al., <i>The Photo-Erasable Memory Switching Effect of Ag Photo-Doped Chalcogenide Glasses</i> , 46 BUL. CHEM. SOC. JAPAN, No. 12, pp. 3662-3665 (December 1973).	

EXAMINER <i>Shuband</i>	DATE CONSIDERED <i>01/08/03</i>
-------------------------	---------------------------------

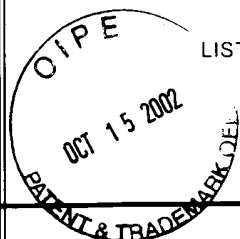
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1672		SERIAL NO. 09/943,199	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; color: black; font-weight: bold; line-height: 1;"> O I P E OCT 15 2002 PATENT & TRADEMARK OFFICE </div> </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
				APPLICANT: Kristy A. Campbell et al.			
				FILING DATE August 29, 2001		GROUP 2818	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
DV	AN		Somogyi et al., <i>Temperature Dependence of the Carrier Mobility in Ag₂Se Layers Grown on</i>				
			NaCl and SiO _x Substrates, 74 ACTA PHYSICA HUNGARICA, No. 3, pp. 243-255 (1994).				
DV	AO		Tai et al., <i>Multilevel Ge-Se film based resist systems</i> , SPIE Vol. 333 SUBMICRON LITHOGRAPHY,				
			pp. 32-39 (March 1982).				
DV	AP		Tai et al., <i>Submicron optical lithography using an inorganic resist/polymer bilevel scheme</i> ,				
			17 J. Vac. Sci. Technol., No. 5, pp. 1169-1176 (Sept./Oct. 1980).				
EXAMINER <i>ghuland</i>			DATE CONSIDERED <i>01/08/03</i>				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1672SERIAL NO.
09/9432,199LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT: Kristy A. Campbell et al.

FILING DATE
August 29, 2001GROUP
2818

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DV	AN		West, DISSERTATION: <i>Electrically Erasable Non-Volatile Memory Via electrochemical Deposition of Multifractal Aggregates</i> , Arizona State University, pp. title page-168 (UMI Co., May 1998).
DV	AO		West et al., <i>Equivalent Circuit Modeling of the $\text{Ag} \text{As}_{0.24}\text{S}_{0.36}\text{Ag}_{0.40} \text{Ag}$ System Prepared by Photodissolution of Ag</i> , 145 J. Electrochem. Soc., No. 9, pp. 2971-2974 (September 1998).
DV	AP		Yoshikawa et al., <i>A new inorganic electron resist of high contrast</i> , 31 APPL. PHYS. LETT., No. 3, pp. 161-163 (August 1977).

EXAMINER

S. Muland

DATE CONSIDERED

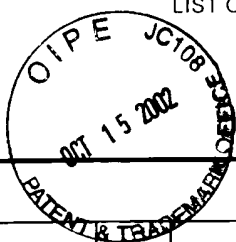
01/08/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1672SERIAL NO.
09/9432,199LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT: Kristy A. Campbell et al.

FILING DATE
August 29, 2001GROUP
2818

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

DV	AN		Yoshikawa et al., Dry development of Se-Ge Inorganic photoresist, 36 APPL. PHYS. LETT., No. 1,
			pp. 107-109 (January 1980).
	AO		
	AP		

EXAMINER

Shelton

DATE CONSIDERED

01/08/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



PTO/SB/08A (10-01)

Approved for use through 10/31/2002 OMB 0651-0031

U. S. Patent and Trademark Office: U. S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Complete if Known		
			Application Number	09/943,199	
			Filing Date	August 29, 2001	
			First Named Inventor	Kristy A. Campbell	
			Art Unit	2818	
			Examiner Name	David Vu	
Sheet	1	of	1	Attorney Docket Number	M4065.0704/P704

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
DV		2002/0168820 A1	11-14-02	Kozicki et al.	
DV		6,469,364 B1	10-22-02	Kozicki	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				

¹ Applicant's unique citation designation number (optional). ² See attached Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²

Examiner Signature	<i>David Vu</i>	Date Considered	01/08/03
-----------------------	-----------------	--------------------	----------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.